



深圳市勋瑞光电科技有限公司

Xunrui Shenzhen Optoelectronics Technology Co., Ltd.

TFT LCM Approval Sheet

PRODUCT SPECIFICATIONS

MODULE NO: H024PQ37E2504

For Customer: _____
Approved by: _____
Signature: _____
Date: _____

Prepared	Checked	Approved	Date



CONTENTS

- **General Information**
- **External Dimensions**
- **Absolute Maximum Ratings**
- **Electrical Characteristics**
- **Timing of Power Supply**
- **Backlight Characteristics**
- **Interface Description**
- **Reliability Test**
- **General Information**

Item	Contents
LCD type	TFT transmissive
Viewing direction	6 O'Clock
Outline area(W*H)	42.30mm * 60.25mm*3.2 (T)
Active area(W*H)	36.72mm * 48.96mm
Number of dots	240*RGB*320
Driver IC	ILI9341
Colors	262K
Interface type	System parallel interface
Input voltage	2.8V



■ Absolute Maximum Ratings

Parameter	Symbol	Min.	Max.	Unit
Supply voltage for logic	IOVcc/Vcc	-0.3	3.6	V
Input voltage	Vin	-0.3	IOVcc+0.3	V
Operating temperature	Vop	-20	70	°C
Storage temperature	Tst	-30	80	°C
Humidity	RH		90% (Max 60°C)	RH

■ Electrical Characteristics

Parameter	Symbol	Min.	Type	Max.	Unit
Supply voltage for logic	Vcc-Vss	2.7	2.8	3.3	V
Supply voltage for I/O	IOVcc	2.7/1.7	2.8/1.8	3.3/1.9	V
Input Current	Idd	-	11.56	23.12	mA
Input voltage 'H' level	Vih	0.8IOVcc	-	IOVcc	V
Input voltage 'L' level	Vil	-0.3	-	0.2IOVcc	°C
Output voltage 'H' level	Voh	0.8IOVcc	-	-	°C
Output voltage 'L' level	Vol	-	-	0.2IOVcc	RH

■ Timing of Power Supply

Please refer to the driver IC specification.

■ Backlight Characteristics

Item	Symbol	Min.	Type	Max.	Unit	Condition
Forward voltage	Vf	3.10	3.15	3.2	V	If=60mA
Luminance	Lv	3200	3500	3800	Cd/m ²	Ta=25°C
Number of LED	-	4			Piece	-
Connection mode	P	0.8IOVcc	-	IOVcc	V	-



Interface Description

Pin NO.	Signal	I/O	Function
1	FMARK	O	Tearing effect output. Be used after writing data to RAM.
2	VCC	P	Power supply
3	VCC	P	Power supply
4	CS	I	Ground.
5	RS	I	- Register and Data select signal
6	WR	I	Write signal.
7	RD	I	Read signal.
8	RESET	I	Reset signal pin.
9	DB0	I/O	Data bus. When in 16bit mode, connected to GND .
10	DB1	I/O	Data bus. When in 16bit mode, connected to GND .
11	DB2	I/O	Data bus. When in 16bit mode, connected to GND .
12	DB3	I/O	Data bus. When in 16bit mode, connected to GND .
13	DB4	I/O	Data bus. When in 16bit mode, connected to GND .
14	DB5	I/O	Data bus. When in 16bit mode, connected to GND .
15	DB6	I/O	Data bus. When in 16bit mode, connected to GND .
16	DB7	I/O	Data bus. When in 16bit mode, connected to GND .
17	DB8	I/O	Data bus.
18	DB9	I/O	Data bus.
19	DB10	I/O	Data bus.
20	DB11	I/O	Data bus.
21	DB12	I/O	Data bus.
22	DB13	I/O	Data bus.
23	DB14	I/O	Data bus.
24	DB15	I/O	Data bus
25	NC		No connection
26	YD	-	TP signal
27	XR	-	TP signal
28	YU	-	TP signal
29	XL	-	TP signal
30	LEDA	P	LED ANODE
31	LEDK1	P	LED CATHODE
32	LEDK2	P	LED CATHODE
33	LEDK3	P	LED CATHODE
34	LEDK4	P	LED CATHODE
35	GND	G	Power GND
36	GND	G	Power GND
37	IM0	-	IM0=0: 16bit ; IM0=1: 8bit.



■ Reliability Test

Test item	Test Condition
High Temperature Storage	$60 \pm 2^\circ\text{C}/48$ hours
Low Temperature Storage	$-10 \pm 2^\circ\text{C}/48$ hours
High Temperature Operating	$45 \pm 2^\circ\text{C}/48$ hours
Low Temperature Operating	$0 \pm 2^\circ\text{C}/48$ hours
Temperature Cycle	$0 \pm 2^\circ\text{C} \sim 50 \pm 2^\circ\text{C} \times 10$ cycles (30min.) (5min.) (30min.)
Damp Proof Test	$50^\circ\text{C} \pm 5^\circ\text{C} \times 90\% \text{RH}/48$ hours
ESD test	Voltage: $\pm 4\text{KV}$ R: 330Ω C: 150pF Air discharge, 10time